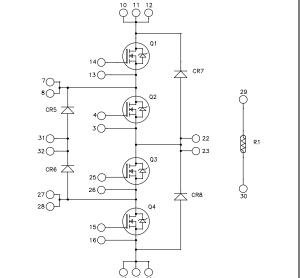


Three level inverter SiC MOSFET Power Module

SiC Power MOSFET:

 $V_{DSS} = 1200V ; R_{DSon} = 49m\Omega @ Tj = 25^{\circ}C$



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All multiple inputs and outputs must be shorted together 10/11/12; 7/8; 27/28; ...

Application

Uninterruptible Power Supplies

Features

- SiC Power MOSFET
 - Low R_{DS(on)}
 - High temperature performance
- SiC Schottky Diode
 - Zero reverse recovery
 - Zero forward recovery
 - Temperature Independent switching behavior
 - Positive temperature coefficient on VF
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring
- AlN substrate for improved thermal performance

Benefits

- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive TC of VCEsat
- Low profile
- **RoHS Compliant**

All ratings @ $T_i = 25^{\circ}C$ unless otherwise specified

O1 to O4 Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter	,	Max ratings	Unit
$V_{ m DSS}$	Drain - Source Breakdown Voltage		1200	V
Ţ	Cantinuana David Comment	$T_c = 25^{\circ}C$	55	
I_D	Continuous Drain Current	$T_c = 80^{\circ}C$	42	A
I_{DM}	Pulsed Drain current		110	
V_{GS}	Gate - Source Voltage		-10/+25	V
R _{DSon}	Drain - Source ON Resistance		49	mΩ
P_{D}	Maximum Power Dissipation	$T_c = 25^{\circ}C$	250	W

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com

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${\bf Q1\ to\ Q4\ Electrical\ Characteristics\ (per\ SiC\ MOSFET)}$

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$; $V_{DS} = 1200V$			25	200	μA
D	Dunin Common on Bosistano	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		40	49	
$R_{DS(on)}$	Drain – Source on Resistance	$I_D = 40A$	$T_j = 150$ °C		75	104	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 2mA$		1.7	2.2		V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	1			500	nA

Q1 to Q4 Dynamic Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V$			1900		
C_{oss}	Output Capacitance	$V_{\rm DS} = 1000 V$			160		pF
C_{rss}	Reverse Transfer Capacitance	f = 1MHz			13		
Q_{g}	Total gate Charge	$V_{GS} = 20V$			98		
Q_{gs}	Gate – Source Charge	$V_{Bus} = 800V$			22		nC
Q_{gd}	Gate – Drain Charge	$I_D = 40A$			36		
$T_{d(on)}$	Turn-on Delay Time	$V_{GS} = -5/+20V$ $V_{Bus} = 800V$			12		
$T_{\rm r}$	Rise Time				14		ns
$T_{d(off)}$	Turn-off Delay Time	$I_D = 40A$		23			
T_{f}	Fall Time	$R_{\rm L}=20\Omega \; ; \; R_{\rm G}=25$	Ω		18		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 600V$	$T_j = 150^{\circ}C$		0.9		mJ
$E_{\rm off}$	Turn off Energy	$I_{D} = 40A$ $R_{G} = 25\Omega$	$T_{j} = 150^{\circ}C$		0.5		mJ
R_{thJC}	Junction to Case Thermal Resistance	e				0.5	°C/W

CR5 & CR6 SiC diode ratings and characteristics (Per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			600			V
I_{RM}	Maximum Reverse Leakage Current	V _R =600V	$T_j = 25^{\circ}C$ $T_i = 175^{\circ}C$		30 60	180 900	μΑ
I_F	DC Forward Current		Tc = 125°C		30		A
$V_{\rm F}$	Diode Forward Voltage	$I_F = 30A$	$T_i = 25^{\circ}C$ $T_i = 175^{\circ}C$		1.6	1.8	V
Q_{C}	Total Capacitive Charge	$I_F = 30A, V_R = 600V$ $di/dt = 1000A/\mu s$			84		nC
C	$f = 1 \text{MHz}, V_R = 200 \text{V}$		200V		195		nЕ
С	Total Capacitance	$f = 1 MHz, V_R = 400V$	400V		150		pF
R_{thJC}	Junction to Case Thermal Resistance					0.8	°C/W

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CR7 & CR8 diode ratings and characteristics (Per SiC diode)

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit	
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			1200			V	
I_{RM}	Maximum Reverse Leakage Current	V _R =1200V	$T_j = 25^{\circ}C$ $T_i = 175^{\circ}C$		96 168	600 3000	μΑ	
I_{F}	DC Forward Current		$Tc = 125^{\circ}C$		30	3000	A	
$V_{\rm F}$	Diode Forward Voltage	$I_F = 30A$	$T_i = 25^{\circ}C$ $T_i = 175^{\circ}C$		1.6 2.3	1.8	V	
Qc	Total Capacitive Charge	$I_F = 30A, V_R = 1200V$ $di/dt = 1500A/\mu s$			240		nC	
C	Total Capacitance	$f = 1MHz, V_R = 200V$		$f = 1 \text{MHz}, V_R = 200 \text{V}$		288		пE
С		$f = 1 MHz, V_R = 400 V$	400V		207		pF	
R_{thJC}	Junction to Case Thermal Resistance					0.50	°C/W	

$Temperature\ sensor\ NTC\ (\text{see application note APT0406 on www.microsemi.com}\).$

Symbol	Characteristic		Min	Typ	Max	Unit
R ₂₅	Resistance @ 25°C	C		50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B _{25/85}	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta B/B$		T _C =100°C		4		%

$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$
 T: Thermistor temperature R_T: Thermistor value at T

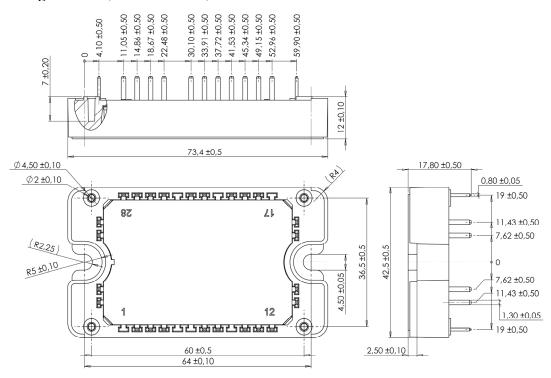
Thermal and package characteristics

Symbol	Characteristic			Min	Typ	Max	Unit
V_{ISOL}	RMS Isolation Voltage, any terminal to c	ase $t = 1 \min_{t = 1}^{\infty} 50$)/60Hz	4000			V
Т	Operating junction temperature range		SiC MOSFET	-40		150	
T_{J}	SiC diode		SiC diode	-40		175	
T_{JOP}	Recommended junction temperature under switching conditions			-40		T _J max -25	°C
T_{STG}	Storage Temperature Range			-40		125	
T_{C}	Operating Case Temperature			-40		125	
Torque	Mounting torque	To heatsink	M4	2		3	N.m
Wt	Package Weight					110	g

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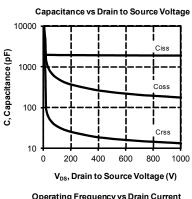


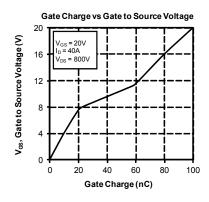
SP3 Package outline (dimensions in mm)

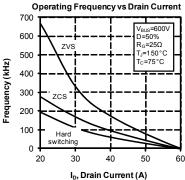


See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

Q1 to Q4 Typical performance curve

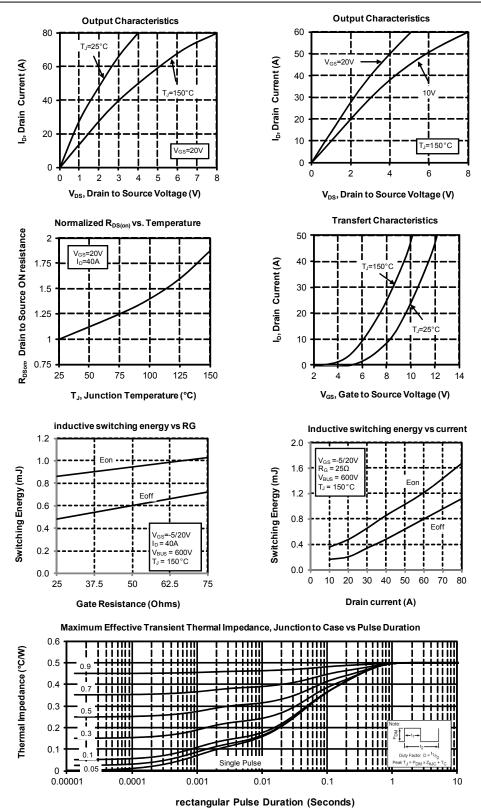






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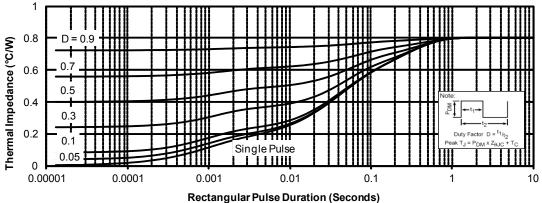


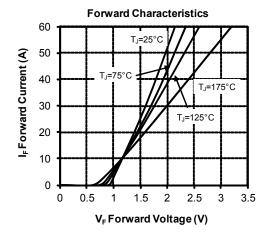
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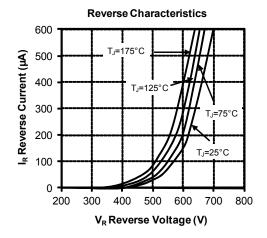


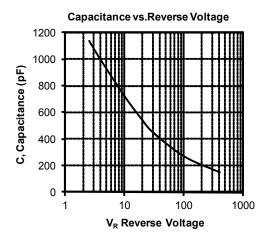
CR5 & CR6 Typical performance curve

Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration





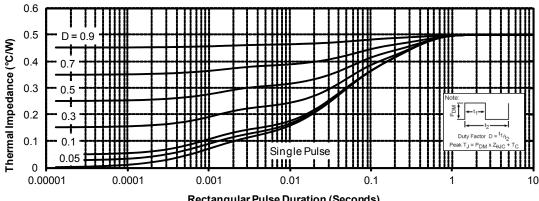




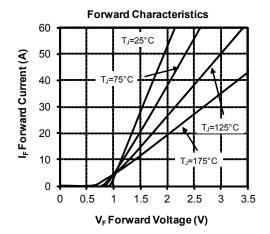


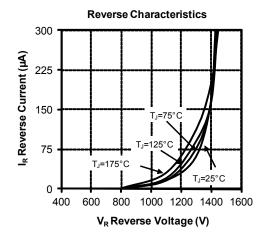
CR7 & CR8 Typical performance curve

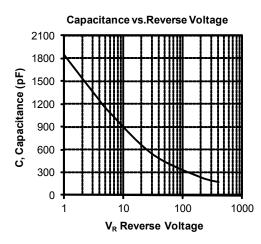
Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration



Rectangular Pulse Duration (Seconds)







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